

EE141-Spring 2010 Digital Integrated Circuits

Lecture 6 Complex Logic

EECS141

Lecture #6

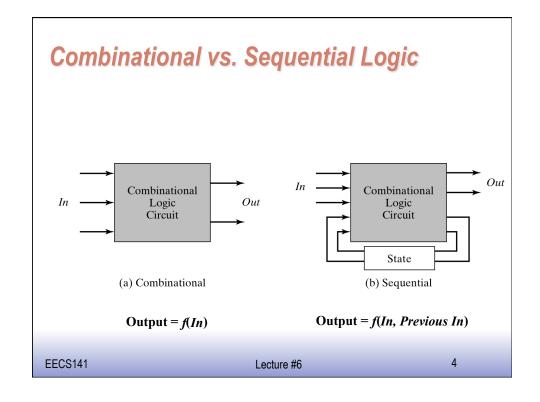
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Administrativia

- □ Lab 3 this week
- □ Midterm on Friday February 19
 - Open book
 - Covering material from start up to complex logic optimization (this lecture and next)

Class Material

- □ Last lecture
 - Sizing inverters
- □ Today's lecture
 - Complex logic
 - Optimizing complex logic
- □ Reading (2.3, 3.3.1-3.3.2)



Static Logic Gates

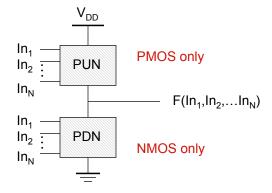
At every point in time (except during the switching transients) each gate output is connected to either V_{DD} or V_{SS} via a low resistive path.

The outputs of the gates assume at all times the value of the Boolean function implemented by the circuit (ignoring, once again, the transient effects during switching periods).

(Will contrast this later to dynamic circuit style.)

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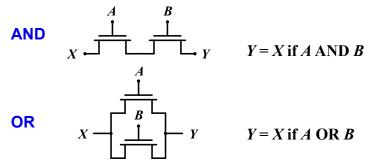
Static Complementary CMOS



PUN and PDN are dual logic networks
PUN and PDN functions are complementary

NMOS Transistors in Series/Parallel Connection

- □ Transistor ↔ switch controlled by its gate signal
 - NMOS switch closes when switch control input is high

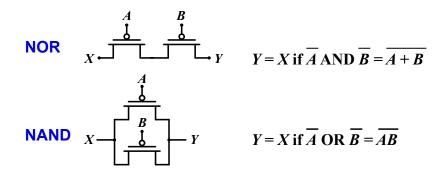


□ NMOS transistors pass a "strong" 0 but a "weak" 1

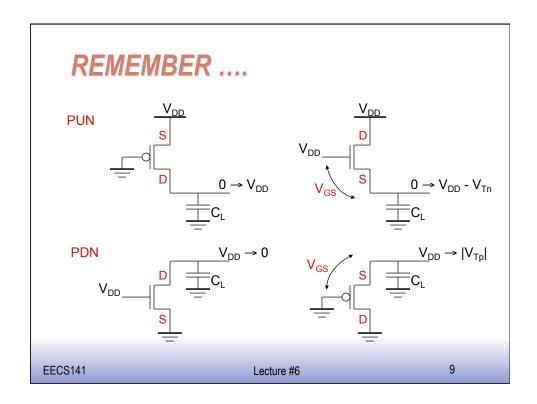
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PMOS Transistors in Series/Parallel Connection

□ PMOS switch closes when switch control is low



□ PMOS transistors pass a "strong" 1 but a "weak" 0



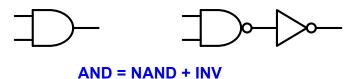
Complementary CMOS Logic Style

□ PUP is the <u>dual</u> to PDN (can be shown using DeMorgan's Theorems)

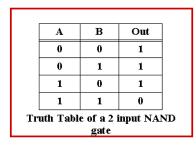
$$\overline{A+B} = \overline{AB}$$

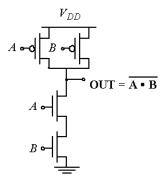
$$\overline{AB} = \overline{A} + \overline{B}$$

□ Static CMOS gates are always inverting



Example Gate: NAND

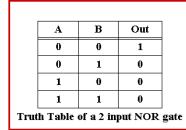


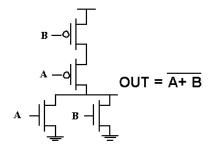


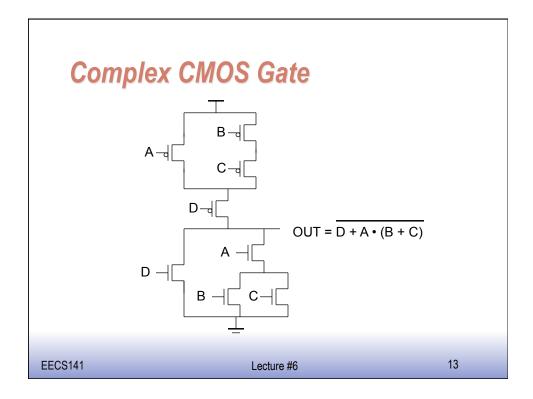
- \square PDN: G = AB \Rightarrow Conduction to GND
- \square PUN: F = \overline{A} + \overline{B} = \overline{AB} \Rightarrow Conduction to V_{DD}
- $\ \ \, \boxdot \ \, \overline{\mathsf{G}(\mathsf{In}_1,\mathsf{In}_2,\mathsf{In}_3,\ldots)} \equiv \mathsf{F}(\overline{\mathsf{In}_1},\overline{\mathsf{In}_2},\overline{\mathsf{In}_3},\ldots)$

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Example Gate: NOR

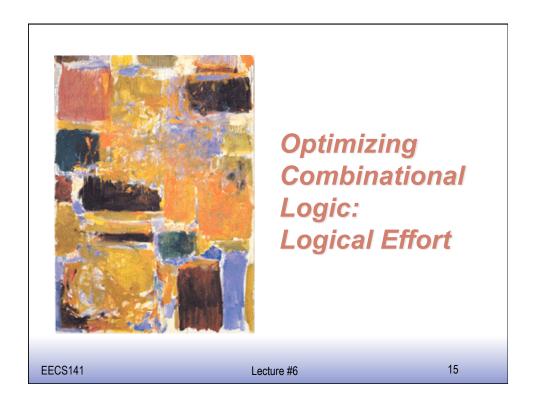


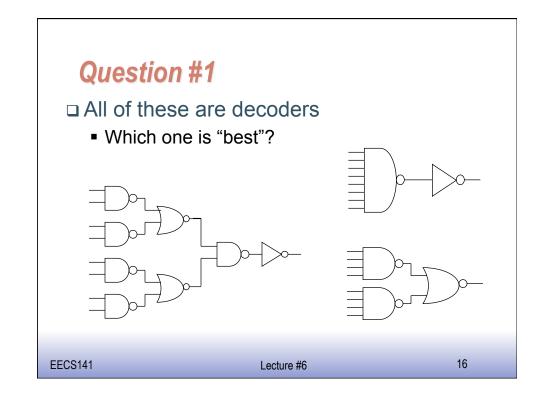




CMOS Properties

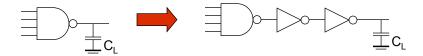
- □ Full rail-to-rail swing
- Symmetrical VTC
- □ Propagation delay function of load capacitance and resistance of transistors
- □ No static power dissipation
- □ Direct path current during switching





Question #2

□ Is it better to drive a big capacitive load directly with the NAND gate, or after some buffering?



- □ Method to answer both of these questions:
 - Logical effort
 - Extension of buffer sizing problem

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Recap: Buffer Sizing

In Out
$$C_1 \longrightarrow C_2 \longrightarrow C_N \longrightarrow C_N \longrightarrow C_L = C_{N+1}$$

$$Delay = t_{inv} \sum_{i=1}^{N} (\gamma + f_i)$$

$$f_i = C_{i+1}/C_i$$

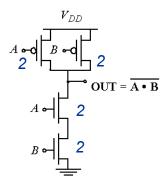
For given *N*: $C_{i+1}/C_i = C_i/C_{i-1}$

To find N: $C_{i+1}/C_i \sim 4$

How to generalize this to any logic path?

Delay Of NAND Gate

$$C_{dnand} = 6C_D$$
 $C_{gnand} = 4C_G = (4/3) C_{ginv}$
 $C_D/C_G = \gamma$



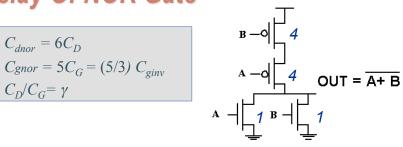
$$\begin{split} \mathbf{t}_{\mathsf{pNAND}} &= kR(C_{int} + C_{L}) \\ &= k(R_{min}/W)(WC_{dnand} + C_{L}) \\ &= k(R_{min}C_{gnand})(C_{dnand}/C_{gnand} + C_{L}(WC_{gnand})) \\ &= k(R_{min}C_{gnand})(\gamma 3/2 + C_{L}(WC_{gnand})) \\ &= t_{inv}(2\gamma + (4/3)f) \end{split}$$

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Delay Of NOR Gate

$$C_{dnor} = 6C_D$$

 $C_{gnor} = 5C_G = (5/3) C_{ginv}$
 $C_D/C_G = \gamma$



$$\begin{aligned} \mathbf{t}_{\mathsf{pNAND}} &= kR(C_{int} + C_{L}) \\ &= k(R_{min}/W)(WC_{dnor} + C_{L}) \\ &= k(R_{min}C_{gnor})(C_{dnor}/C_{gnor} + C_{L}(WC_{gnor})) \\ &= k(R_{min}C_{gnor})(\gamma 6/5 + C_{L}(WC_{gnor})) \\ &= t_{inv}(2\gamma + (5/3)f) \end{aligned}$$

Logical Effort

$$t_{pgate} = t_{inv} (p\gamma + LE \times f)$$

Measure everything in units of t_{inv} (divide by t_{inv}):

p – intrinsic delay ($k\gamma_g$) - gate parameter $\neq f(W)$ LE – logical effort (k) – gate parameter $\neq f(W)$ f – electrical effort (effective fanout)

Normalize everything to an inverter:

$$LE_{inv} = 1$$
, $p_{inv} = \gamma$

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Delay in a Logic Gate

Gate delay:

Delay = EF + p (measured in units of t_{inv})
effective fanout intrinsic delay

Effective fanout:

$$EF = LE f$$
logical effort electrical fanout = C_{out}/C_{in}

Logical effort is a function of topology, independent of sizing Effective fanout is a function of load/gate size

Logical Effort

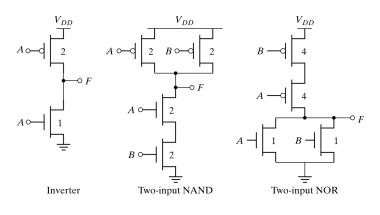
- □ Inverter has the smallest logical effort and intrinsic delay of all static CMOS gates
- □ Logical effort LE is defined as:
 - $\bullet (R_{eq,gate}C_{in,gate})/(R_{eq,inv}C_{in,inv})$
 - Easiest way to calculate (usually):
 - Size gate to deliver same current as an inverter, take ratio of gate input capacitance to inverter capacitance
- □ LE increases with gate complexity

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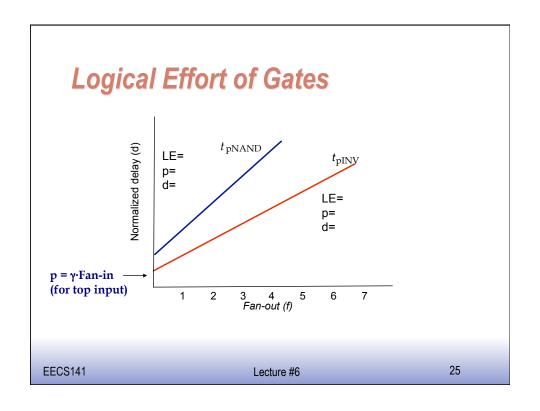
Logical Effort

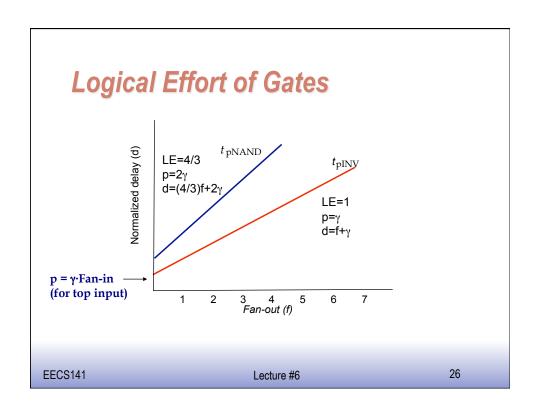
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Calculating LE by sizing for same drive strength:



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Logical Effort

Gate Type	Number of Inputs			
	1	2	3	n
Inverter	1			
NAND		4/3	5/3	(n+2)/3
NOR		5/3	7/3	(2n + 1)/3
Multiplexer		2	2	2
XOR		4	12	

From Sutherland, Sproull

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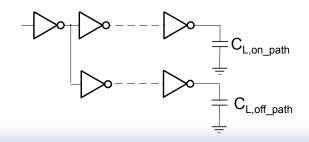
Gate Sizing Convention

- □ Need to set a convention:
 - What does a gate of size '2' mean?
- □ For an inverter it is clear:
 - $C_{inv} = 2$, $R_{inv} = \frac{1}{2}$
- □ For a gate, two possibilities:
 - C_{gate} = 2C_{inv}
 - $R_{gate} = R_{inv}/2$
- □ In my notes, size $\equiv C_{gate}/C_{inv}$
 - Size 2 gate has twice the input capacitance of a unit inverter

Add Branching Effort

Branching effort:

$$b = \frac{C_{L,on-path} + C_{L,off-path}}{C_{L,on-path}}$$



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Multistage Networks

$$Delay = \sum_{i=1}^{N} (p_i + LE_i \cdot f_i)$$

Effective fanout: $EF_i = LE_i f_i$

Path electrical fanout: $F = C_{out}/C_{in}$

Path logical effort: $\Pi LE = LE_1 LE_2 ... LE_N$

Branching effort: $\Pi B = b_1 b_2 ... b_N$

Path effort: $PE = \Pi LE \Pi B F$

Path delay $D = \Sigma d_i = \Sigma p_i + \Sigma E F_i$

Optimum Effort per Stage

When each stage bears the same effort:

$$EF^N = PE$$

$$EF = \sqrt[N]{PE}$$

Effective fanouts: $LE_1f_1 = LE_2f_2 = ... = LE_Nf_N$

Minimum path delay

$$\hat{D} = \sum_{i=1}^{N} (LE_i f_i + p_i) = N \cdot PE^{1/N} + \sum_{i=1}^{N} p_i$$

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Optimal Number of Stages

For a given load, and given input capacitance of the first gate Find optimal number of stages and optimal sizing

$$D = N \cdot PE^{1/N} + \sum p_i$$

Remember: we can always add inverters to the end of the chain

The 'best effective fanout' $EF = PE^{1/\hat{N}}$ is still around 4 (3.6 with γ =1)

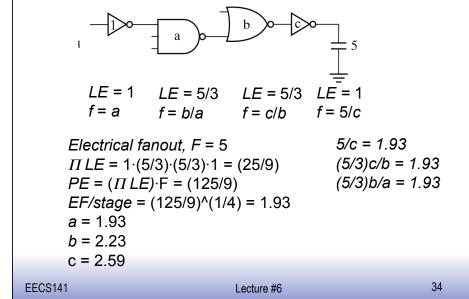
Example: Optimize Path

LE = 1 LE =
$$5/3$$
 LE = $5/3$ LE = $1/3$ LE

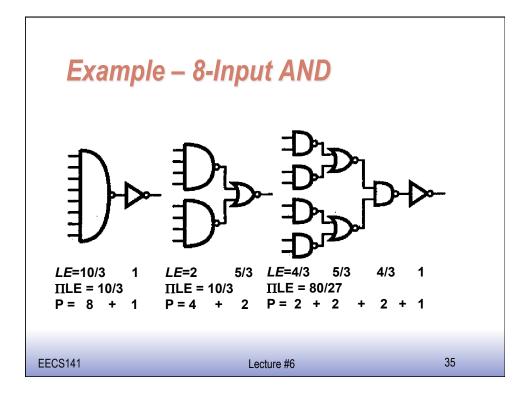
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Example: Optimize Path

c =



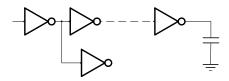
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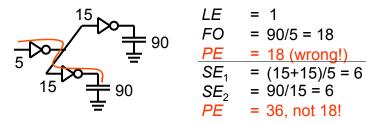
Add Branching Effort

Branching effort:

$$b = \frac{C_{on-path} + C_{off-path}}{C_{on-path}}$$



Branching Example 1



Introduce new kind of effort to account for branching:

- Branching Effort: $b = \frac{C_{\text{on-path}} + C_{\text{off-path}}}{C_{\text{on-path}}}$
- Path Branching Effort: $B = \prod b_i$

Now we can compute the path effort:

• Path Effort: $PE = \prod LE \cdot FO \cdot B$

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Branching Example 2

Select gate sizes y and z to minimize delay from A to B

Logical Effort: $LE = (4/3)^3$

Electrical Effort: $FO = C_{out}/C_{in} = 9$

Branching Effort: B = 2.3 = 6

Path Effort: $PE = \prod LE \cdot FO \cdot B = 128$

Best Stage Effort: $SE = PE^{1/3} \approx 5$

Delay: D = 3.5 + 3.2 = 21

Work backward for sizes:

$$v = \frac{3z \cdot (4/3)}{5} = 1.90$$

Method of Logical Effort

- \Box Compute the path effort: PE = $(\Pi LE)BF$
- \Box Find the best number of stages $N \sim \log_4 PE$
- \Box Compute the effective fanout/stage EF = PE^{1/N}
- □ Sketch the path with this number of stages
- □ Work either from either end, find sizes: $C_{in} = C_{out}^* LE/EF$

Reference: Sutherland, Sproull, Harris, "Logical Effort, Morgan-Kaufmann 1999.